



# Japan Traceability Committee Meeting Summary and Minutes

#### Japan Spring Meetings 2013 April 23, 2013, 13:00 - 15:00 JPR Bldg. Conference Room1, SEMI Japan Office, Tokyo, Japan

#### **Next Committee Meeting**

August 6, 2013, 13:00-15:00 Japan Standards Time JPR Bldg. Conference Room1, SEMI Japan Office, Tokyo, Japan

#### **Committee Announcements (optional)**

None

#### **Table 1 Meeting Attendees**

**Co-Chairs:** Yoichi Iga (Renesus Electronics), Hirokazu Tsunobuchi (Keyence) **SEMI Staff:** Hirofumi Kanno

Company	Last	First	Company	Last	First
Renesus Electronics	Iga	Yoichi	Keyence	Tsunobuchi	Hirokazu
Fujitsu Semiconductor	Iida	Kiyokazu	Fujitsu Semiconductor	Hirasue	Terumi
Acteon	Komatsu	Shoji	SUMCO	Nakai	Tetsuya

#### Table 2 Leadership Changes

	Group
JA Anti-Counterfeiting Task Force disbandment	

#### Table 3 Ballot Results (or move to Section 4, Ballot Review)

**Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review. **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting.

Documer	t # Document Title	Committee Action
5487	New Specification for Basic Protocols to Support the Interoperation of Traceability Systems Necessary for Managing Product Identity throughout the Life Cycle of Objects Using Digital Signatures and Time Stamps	Failed and returned to the Task Force for re- work.

#### Table 4 Authorized Ballots (or move to Section 7, New Business)

None

#### Table 5 Authorized Activities (or move to Section 7, New Business)

5594 SNARF Japan PV New Standard: Guide for Smart Label for PV Traceability Traceability	#	Туре	SC/TF/WG	Details
Task Force	5594		Traceability	New Standard: Guide for Smart Label for PV Traceability

Note: SNARFs and TFOFs are available for review on the SEMI Web site at: <u>http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF</u>

#### Table 6 New Action Items (or move to Section 8, Action Item Review)

None





#### Table 7 Previous Meeting Actions Items (or move to Section 8, Action item Review)

None

#### 1 Welcome, Reminders, and Introductions

Yoichi Iga called the meeting to order at 13:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

#### 2 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting.

Motion:To approve minutes of the previous meeting as written.By / 2<sup>nd</sup>:Hirokazu Tsunobuchi (Keyence) / Kiyokazu Iida (Fujitsu Semiconductor)Discussion:NoneVote:3:0

Attachment: 01, Minutes\_dec.2012

#### 3 Liaison Reports

#### 3.1 North America Traceability Committee

Hirofumi Kanno (SEMI) reported for the North America Traceability Committee. Of note:

- Committee Structure & Leaders
- Meeting Information
- Ballot Results
- New SNARFs
- Upcoming Ballots

Attachment: 02, NA Traceability Liaison Report20130411

#### 3.2 450 mm Notch Free Wafer Report from Japan Silicon Wafer Committee

Tetsuya Nakai (SUMCO) reported for the current discussion for 450 mm Notch Free wafer in the Global Silicon Wafer Committee.

From the next committee meeting, the committee will add new liaison report for 450 mm Wafer Task Force under Silicon Wafer Committee in the Liaison Reports section.

#### 3.3 SEMI Staff Report

Hirofumi Kanno (SEMI) gave the SEMI Staff Report. Of note:

- Global SEMI Events
- Standards Meetings during SEMICON West
- Ballot Critical Dates
- Publication Update
- ISC A&R SC Summary February 2013
- Recent Regulations & Procedure Guide Revisions
- Contact Information

# Semi

# SEMI\* International Standards

#### Attachment: 03, SEMI Staff Report 2013 April R1.0

# 4 Ballot Review

4.1 Document 5487, New Specification for Basic Protocols to Support the Interoperation of Traceability Systems Necessary for Managing Product Identity throughout the Life Cycle of Objects Using Digital Signatures and Time Stamps

#### Tallies

	Return		Distribution		Return Rate	
Yellow	28	÷	46	=	60.9%	>=60%
Lilac & Others	18					
Total Vote	46					
Reject	1					
Accept	17					

**NOTICE:** This document met the 90% approval condition set forth in Section 9.6.3 of the *Regulations Governing SEMI Standards Committees* at the close of balloting.

**NOTICE:** This document did NOT meet the 90% approval condition set forth in Section 9.6.3 of the *Regulations Governing SEMI Standards Committees* at the close of balloting.

#### **Rejects/Negatives**

The creation of this standard, I believe, extends beyond the perview of the SEMI Traceability effort. Specifically, I am currently of the opinion that the SEMI standards in traceability rightfully lie in the realm of semiconductor production. This is not to say that supply chain traceability is not of extreme value. Rather, it is just not within the SEMI Traceability teams' scope.

Comments

None

NOTICE: Items from "Reject" votes that are clearly marked by the voter as comments are included here.

Attachment: 04, Voting Procedural Sheet for 5487

#### 5 Subcommittee & Task Force Reports

5.1 5 Years Review Task Force

Hirokazu Tsunobuchi (Keyence) reported no update for the Task Force.

5.2 JA Anti-Counterfeiting Task Force

Yoichi Iga (Renesas Electronics) reported that there has no update for the JA Anti-Counterfeiting Task Force.

Due to the NA Anti-Counterfeiting Task Force was disbanded. Yoichi Iga proposed that the Japan Anti-Counterfeiting Task Force should be disbanded.

Motion:	Disbandment of the Japan Anti-Counterfeiting Task Force
By / 2 <sup>nd</sup> :	Hirokazu Tsunobuchi (Keyence), Kiyokazu Iida (Fujitsu Semiconductor)
Discussion:	None



Vote:



# 5.3 JA PV Traceability Task Force

3:0

Yoichi Iga (Renesas Electronics) reported for the JA PV Traceability Task Force.

Kiyokazu Iida (Fujitsu Semiconductor) proposed the new SNSARF for guide for smart label for PV Traceability.

Motion:To approve SNARF for Guide for Smart Label for PV TraceabilityBy / 2<sup>nd</sup>:Kiyokazu Iida (Fujitsu Semiconductor) / Hirokazu Tsunobuchi (Keyence)Discussion:NoneVote:3:0Attachment:05, Minutes of JA PV Traceability TF

# 6 Old Business

None

# 7 New Business

None

# 8 Action Item Review

8.1 Open Action Items

None

8.2 New Action Items

None

# 9 Next Meeting and Adjournment

The next meeting of the Japan Traceability committee is scheduled for August 6, 130–15:00 at SEMI Japan Office, Tokyo, Japan





Respectfully submitted by: Hirofumi Kanno SEMI Japan Phone: +81.3222.5862 Email: hkanno@semi.org

Minutes approved by:

<name> (<company>), Co-chair</company></name>	<date approved=""></date>				
<name> (<company>), Co-chair</company></name>	<date approved=""></date>				

# Table 8 Index of Available Attachments #1

#	Title	#	Title
01	Minutes_dec.2012		
02	NA Traceability Liaison Report20130411		
03	SEMI Staff Report 2013 April R1.0		
04	Voting Procedural Sheet for 5487		
05	Minutes of JA PV Traceability TF		

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.